

### **Rochester Electronics Manufactured Components**

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

### **Quality Overview**

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
  - Class Q Military
  - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
  - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

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The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

# SN54LS114A, SN54S114, SN74LS114A, SN74S114A DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET, COMMON CLEAR, AND COMMON CLOCK

MARCH 1973—REVISED MARCH 1988

- Fully Buffered to Offer Maximum Isolation from External Disturbance
- Package Options Include Ceramic Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

## description

These devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset and clear inputs sets or resets the outputs regardless of the levels of the other inputs. When preset and clear are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by tying J and K high.

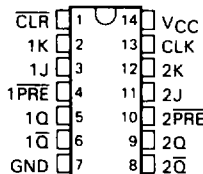
The SN54LS114A and SN54S114 are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . The SN74LS114A and SN74S114A are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

FUNCTION TABLE

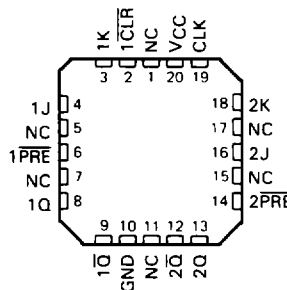
INPUTS					OUTPUTS	
PRE	CLR	CLK	J	K	Q	$\bar{Q}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H <sup>†</sup>	H <sup>†</sup>
H	H	↓	L	L	Q <sub>0</sub>	$\bar{Q}_0$
H	H	↓	H	L	H	L
H	H	↓	L	H	L	H
H	H	↓	H	H	TOGGLE	TOGGLE
H	H	H	X	X	Q <sub>0</sub>	$\bar{Q}_0$

<sup>†</sup>The output levels in this configuration are not guaranteed to meet the minimum levels for  $V_{OH}$  if the lows at preset and clear are near  $V_{IL}$  minimum. Furthermore, this configuration is nonstable; that is, it will not persist when either preset or clear returns to its inactive (high) level.

SN54LS114A, SN54S114 . . . J OR W PACKAGE  
SN74LS114A, SN74S114A . . . D OR N PACKAGE  
(TOP VIEW)

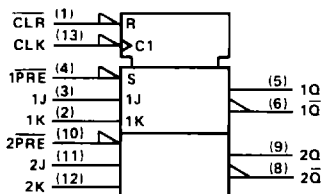


SN54LS114A, SN54S114 . . . FK PACKAGE  
(TOP VIEW)



NC—No internal connection

## logic symbol<sup>†</sup>



<sup>†</sup>This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

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PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

TEXAS  
INSTRUMENTS

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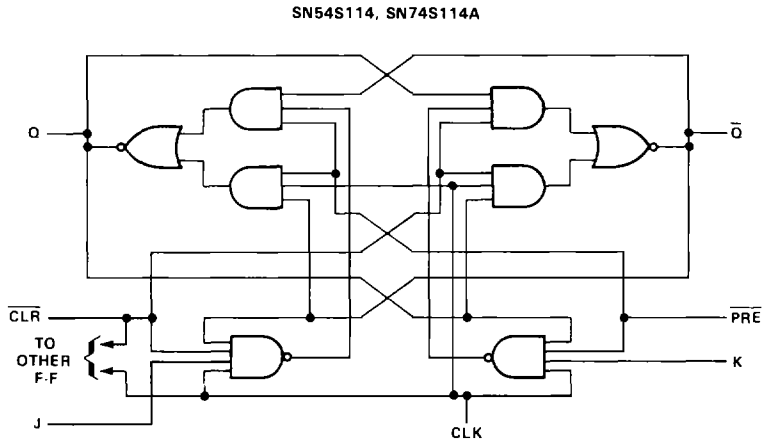
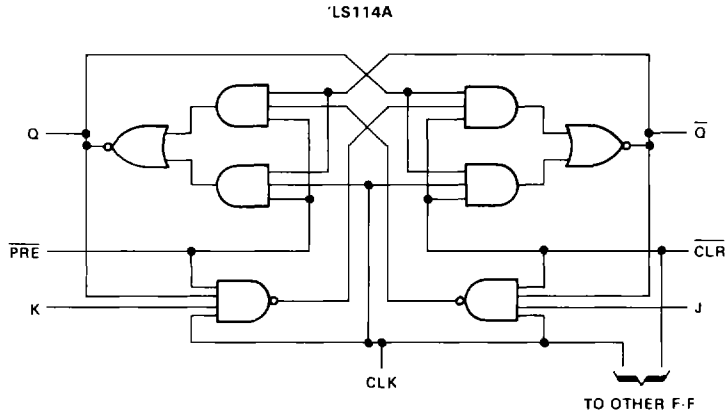
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**SN54LS114A, SN54S114, SN74LS114A, SN74S114A**  
**DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS**  
**WITH PRESET, COMMON CLEAR, AND COMMON CLOCK**

logic diagram (positive logic)

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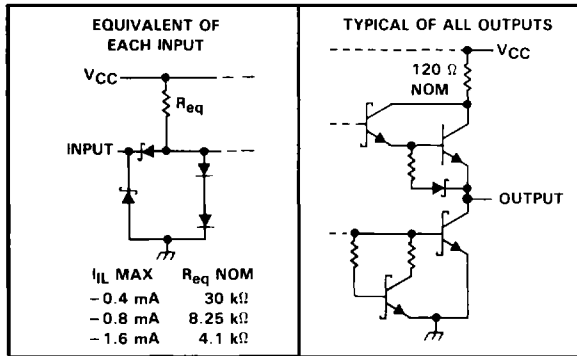
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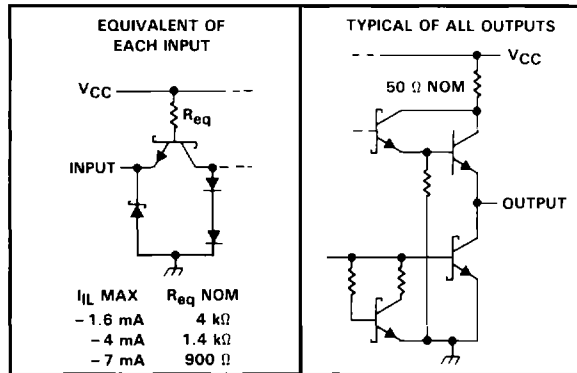
**SN54LS114A, SN54S114, SN74LS114A, SN74S114A  
DUAL J-K NEGATIVE EDGE-TRIGGERED FLIP-FLOPS  
WITH PRESET, COMMON CLEAR, AND COMMON CLOCK**

schematics of inputs and outputs

'LS114A



SN54S114, SN74S114A



**absolute maximum ratings over operating free-air temperature range (unless otherwise noted)**

Supply voltage, $V_{CC}$ (see Note 1)	7 V
Input voltage: 'LS114A	7 V
SN54S114, SN74S114A	5.5 V
Operating free-air temperature range: SN54'	- 55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	- 65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

**SN54LS114A, SN74LS114A**  
**DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS**  
**WITH PRESET, COMMON CLEAR, AND COMMON CLOCK**

**recommended operating conditions**

		SN54LS114A			SN74LS114A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V <sub>IH</sub>	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage			0.7			0.8	V
I <sub>OH</sub>	High-level output current			-0.4			-0.4	mA
I <sub>OL</sub>	Low-level output current			4			8	mA
f <sub>clock</sub>	Clock frequency	0	30		0	30		MHz
t <sub>w</sub>	Pulse duration	CLK	20		20			ns
		PRE or CLR low	25		25			
t <sub>su</sub>	Set up time-before CLK↓	Data high or low	20		20			ns
		CLR inactive	25		25			
		PRE inactive	20		20			
t <sub>h</sub>	Hold time-data after CLK↓	0			0			ns
T <sub>A</sub>	Operating free-air temperature	-55	125		0	70		°C

**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER		TEST CONDITIONS <sup>1</sup>		SN54LS114A		SN74LS114A		UNIT	
				MIN	TYP <sup>2</sup>	MAX	MIN		TYP <sup>2</sup>
V <sub>IK</sub>		V <sub>CC</sub> = MIN, I <sub>I</sub> = -18 mA			-1.5		-1.5	V	
V <sub>OH</sub>		V <sub>CC</sub> = MIN, I <sub>OH</sub> = -0.4 mA	V <sub>IH</sub> = 2 V, V <sub>IL</sub> = MAX.		2.5	3.4	2.7	3.4	V
V <sub>OL</sub>		V <sub>CC</sub> = MIN, I <sub>OL</sub> = 4 mA	V <sub>IL</sub> = MAX, V <sub>IH</sub> = 2 V.		0.25	0.4	0.25	0.4	V
		V <sub>CC</sub> = MIN, I <sub>OL</sub> = 8 mA	V <sub>IL</sub> = MAX, V <sub>IH</sub> = 2 V.				0.35	0.5	
I <sub>I</sub>	J or K	V <sub>CC</sub> = MAX, V <sub>I</sub> = 7 V				0.1		0.1	mA
	CLR					0.6		0.6	
	PRE					0.3		0.3	
	CLK					0.8		0.8	
I <sub>IH</sub>	J or K	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7 V				20		20	μA
	CLR					120		120	
	PRE					60		60	
	CLK					160		160	
I <sub>IL</sub>	J or K	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4 V				-0.4		-0.4	mA
	CLR					-1.6		-1.6	
	PRE					-0.8		-0.8	
	CLK					-1.6		-1.6	
I <sub>OS</sub> <sup>5</sup>		V <sub>CC</sub> = MAX, See Note 2				-20		-100	mA
I <sub>CC</sub> (Total)		V <sub>CC</sub> = MAX, See Note 3				4		6	mA

<sup>1</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions

<sup>2</sup> All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C

<sup>5</sup> Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second

NOTES: 2 For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V<sub>O</sub> = 2.25 V and 2.125 V for the '54 family and the '74 family, respectively with the minimum and maximum limits reduced to one half of their stated values

3 With all outputs open, I<sub>CC</sub> is measured with the Q and Q̄ outputs high in turn. At the time of measurement, the clock input is grounded

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**SN54LS114A, SN74LS114A**  
**DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS**  
**WITH PRESET, COMMON CLEAR, AND COMMON CLOCK**

switching characteristics,  $V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$  (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$				30	45		MHz
$t_{PLH}$	CLR, PRE or CLK	Q or $\bar{Q}$	$R_L = 2\text{ k}\Omega$ , $C_L = 15\text{ pF}$		15	20	ns
$t_{PHL}$					15	20	ns

NOTE 4: Load circuit and voltage waveforms are shown in Section 1.

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TTL Devices

**SN54S114, SN74S114A**  
**DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS**  
**WITH PRESET, COMMON CLEAR, AND COMMON CLOCK**

**recommended operating conditions**

		SN54S114			SN74S114A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V <sub>IH</sub>	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage	0.8			0.8			V
I <sub>OH</sub>	High-level output current	-1			-1			mA
I <sub>OL</sub>	Low-level output current	20			20			mA
t <sub>w</sub>	Pulse duration	CLK	6		6		ns	
		CLK low	6.5		6.5			
		PRE or CLR low	8		8			
t <sub>su</sub>	Setup time	7			7			ns
t <sub>h</sub>	Hold time-data after CLK.	0			0			ns
T <sub>A</sub>	Operating free-air temperature	-55		125	0		70	°C

**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

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**TTL Devices**

PARAMETER		TEST CONDITIONS <sup>1</sup>		SN54S114		SN74S114A		UNIT
				MIN	TYP <sup>2</sup>	MAX	MIN	
V <sub>IK</sub>		V <sub>CC</sub> = MIN.	I <sub>I</sub> = -18 mA	-1.2		-1.2		V
V <sub>OH</sub>		V <sub>CC</sub> = MIN. I <sub>OH</sub> = -1 mA	V <sub>IH</sub> = 2 V. V <sub>IL</sub> = 0.8 V.	2.5	3.4	2.7	3.4	V
V <sub>OL</sub>		V <sub>CC</sub> = MIN. I <sub>OL</sub> = 20 mA	V <sub>IH</sub> = 2 V. V <sub>IL</sub> = 0.8 V.	0.5		0.5		V
I <sub>I</sub>		V <sub>CC</sub> = MAX.	V <sub>I</sub> = 5.5 V	1		1		mA
I <sub>IH</sub>	J or K	V <sub>CC</sub> = MAX.	V <sub>I</sub> = 2.7 V	50		50		μA
	CLR			200		200		
	PRE			100		100		
	CLK			200		200		
I <sub>IL</sub>	J or K	V <sub>CC</sub> = MAX.	V <sub>I</sub> = 0.5 V	-1.6		-1.6		mA
	CLR			-14		-14		
	PRE			-7		-7		
	CLK			-8		-8		
I <sub>OS</sub> <sup>3</sup>		V <sub>CC</sub> = MAX		-40	-100	-40	-100	mA
I <sub>CC</sub> <sup>4</sup>		V <sub>CC</sub> = MAX.	See Note 3	15	25	15	25	mA

<sup>1</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

<sup>2</sup> All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

<sup>3</sup> Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

<sup>4</sup> Values are average per flip-flop.

NOTE 3: With all outputs open, I<sub>CC</sub> is measured with the Q and  $\bar{Q}$  outputs high in turn. At the time of measurement, the clock input is grounded.

**SN54S114, SN74S114**  
**DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS**  
**WITH PRESET, COMMON CLEAR, AND COMMON CLOCK**

switching characteristics,  $V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$  (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\max}$			$R_L = 280\ \Omega$ $C_L = 15\ \text{pF}$	80	125		MHz
$t_{PLH}$	$\overline{\text{PRE}}$ or $\overline{\text{CLR}}$	Q or $\overline{\text{Q}}$		4	7		ns
$t_{PHL}$	$\overline{\text{PRE}}$ or $\overline{\text{CLR}}$ (CLK high)	$\overline{\text{Q}}$ or Q		5	7		ns
	$\overline{\text{PRE}}$ or $\overline{\text{CLR}}$ (CLK low)			5	7		
$t_{PLH}$	CLK	Q or $\overline{\text{Q}}$		4	7		ns
$t_{PHL}$				5	7		ns

NOTE 4: Load circuit and voltage waveforms are shown in Section 1.

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